

AGD-315D V2

Environment Test Report

Report NO: 15P020009

Summary	<p><input checked="" type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p> <p>Comment: _____</p>
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Issue date

2015-05-04

Approval

KJ Wang

Test Engineer

Rex Chang/Juno

Test item list

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Testing Result

Num	Test item list	Result	Remark
1	High Temperature operation test	Pass	
2	Temperature variation operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

Configuration of EUT

Num	Item	Spec
1.	Rugged Touch Display	AGD-315D V2
	1. LCD	TFT 15".MITSUBISHI. AC150 XA02 1024*768. 18 & 24 Bits 1ch Ivds (450cd/m2)
	2. Touch Screen Control Board	EETI control board (USB/RS232 auto-detect board)
	3. A/D Board	ADG/ACD Series. RGBTECH.F2281L-14
	4. Power Board	PER-P17D Rev. B1.0_0_0
2.	Adapter	FSP120-AAB
3.	Equipment	Embedded motherboard with Intel Atom D2250 /1.86GHz
	1. Main Board	BOXER-6914 A1.0
	2. BIOS Ver.	BOXER-6914 R1.0 (B914AM10)(03/04/2015)
	3. Test Softwar :	Windows XP / Run 3DMark06

System Picture



High Temperature Operation test

Test Date: 04-29~30-2015

Test Product: AGD-315D V2

Test Site: AAEON QE Dept.

Test Standard: Refer to IEC 68-2-2 Testing procedures
Test Bd: Dry Heat Test (Operation)

Test Equipment:

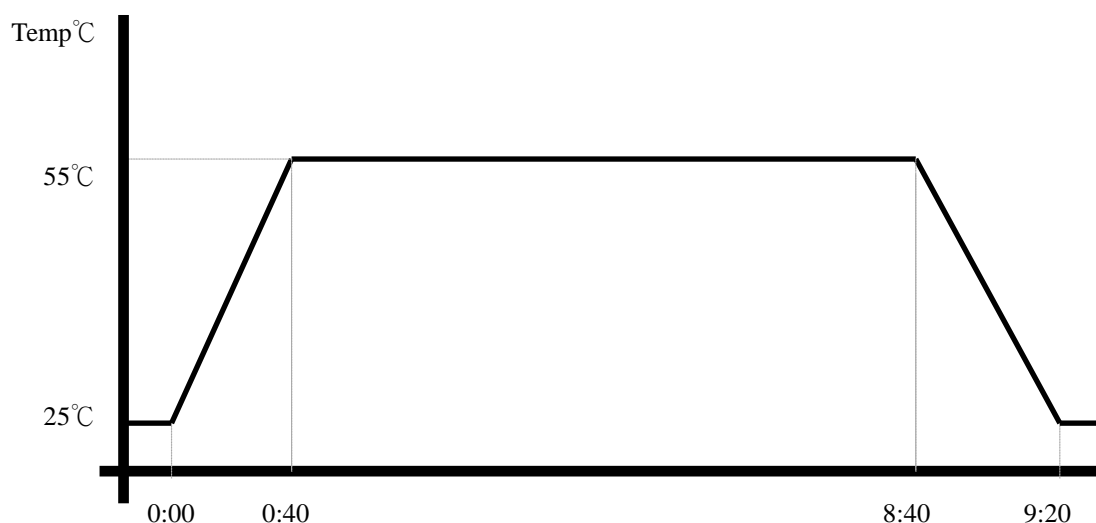
Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)
Model: THS-D7S-100+1 N2
Date of Calibration: 10/09/'14
Serial Number: 3898

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 11/09/2014
Serial Number: 12A32319

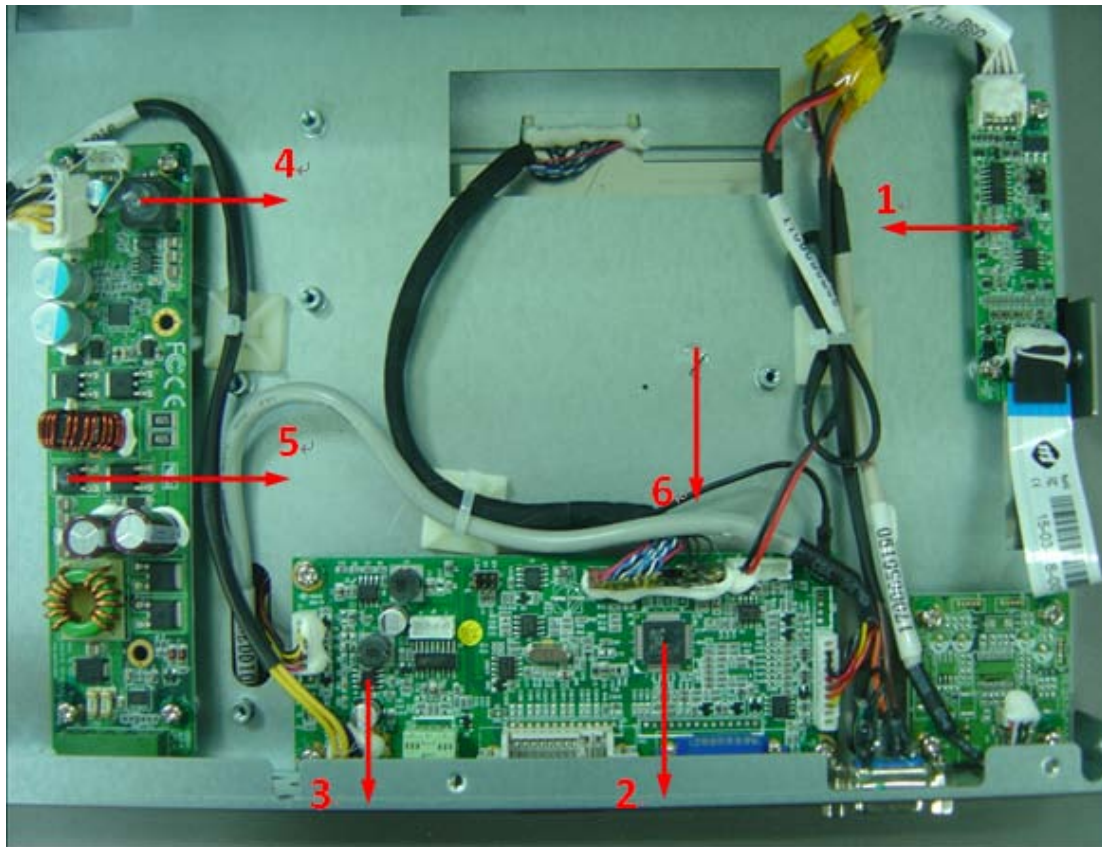
Testing Item:

1. Test Temperature: 55°C
2. Test Times: 8Hrs
3. Test Software: Windows XP / Run 3DMark06
4. Test Environment Curve:



High Temperature Operation test

Measuring Thermal Couple Position :



High Temperature Operation test

AGD-315D V2 (With 0.5m/sec airflow)

Thermal profile data:

Point	Temp. Stage(°C)	Spec	55	25
Touch Screen Control Board				
01. U4 – EETI S458XRUP		85	62.1	32.1
F2281L-14 AD Board				
02. U9 - 1920 scaler, RTD2281L		85	77.9	47.9
03. U1 – Eutech Microelectronics EUP3484S Converter		85	67.3	37.3
POWER BORAD .PER-P17D B1_0_0				
04. L1- COIL. SMD.GOTREND.GSDRH-127-P-T-150M		85	62.1	32.1
05. Q5- PWR.SMD.TO-252AA.N-Channel MOSFET.FAIRCHILD.FDD5670		125	64.2	34.1
06. Control Box Inside Air Temperature		N/A	58.4	28.4
07. Control Box External Surface		N/A	56.5	26.5
08. Chamber Air Temperature		N/A	54.8	24.8
Note(*): 1. "Tc" indicates the component's case maximum temperature value specified in its datasheet. 2. "Tm" indicates the measured Tc value under working environmental temperature within product specification. 3. Judgment Criteria: - Fail : $T_m > T_c$; The measured value is over specification. - Margin Pass : $T_c > T_m > T_c - 5^\circ\text{C}$; The measured value is within specification with margin. It is strongly recommended to add thermal dissipation design for better reliability. - Pass : $T_m < T_c - 5^\circ\text{C}$; The measured value is with safety margin. 4. Defect NO.				

Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-315D V2)

Test Result:

No problem was found during the temperature rise operation test.

Temperature variation operation test

Test Date: 04-27~29-2015

Test Product: AGD-315D V2

Test Site: AAEON QE Dept.

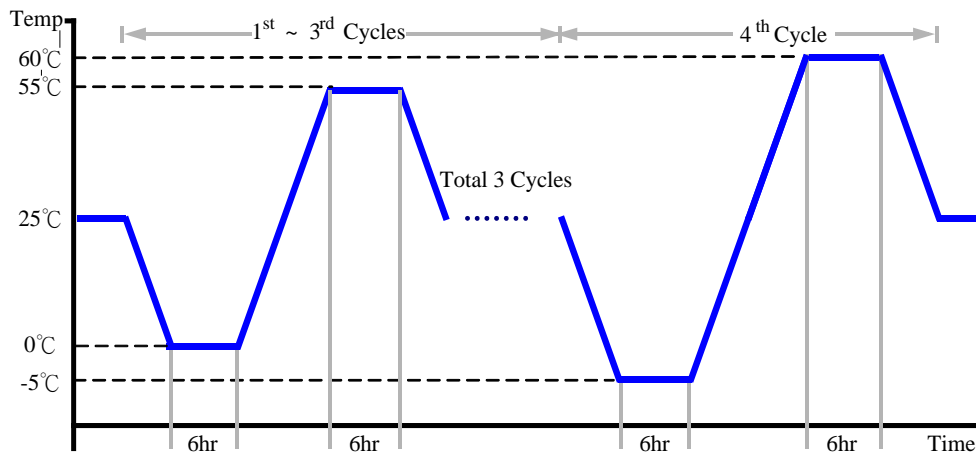
Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/09/14
Serial Number: 2582

Test Condition:

1. Test Low Temperature: 0°C (1~3 cycles)
-5°C (4th cycle)
2. Test High Temperature: 55°C (1~3 cycles)
60°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Software: Windows XP / Run 3DMark06
7. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-315D)

Test Result:

No problem was found during the temperature operation cycle test.

High temperature storage test

Test Date: 04-25~27-2015

Test Product: AGD-315D V2

Test Site: AAEON QE Dept..

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

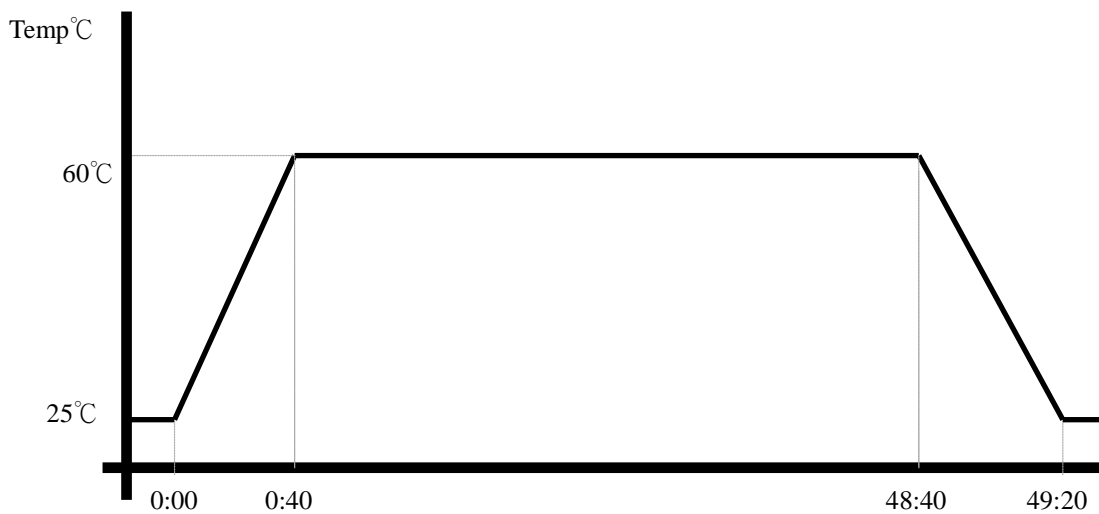
Model: THS-D4H+-100

Date of Calibration: 10/09/14

Serial Number: 2582

Testing Item:

5. Test Temperature: 60°C
6. Test Times: 48Hrs
7. Test Software: Windows XP / Run 3DMark06
8. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-315D V2)

Test Result:

No problem was found after the high temperature storage test.

Low temperature storage test

Test Date: 04-23~25-2015

Test Product: AGD-315D V2

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D4H+-100

Date of Calibration: 10/09/14

Serial Number: 2582

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run 3DMark06
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-315D V2)

Test Result:

No problem was found after the low temperature storage test.

Humidity test

Test Date: 04-21~23-2015

Test Product: AGD-315D V2

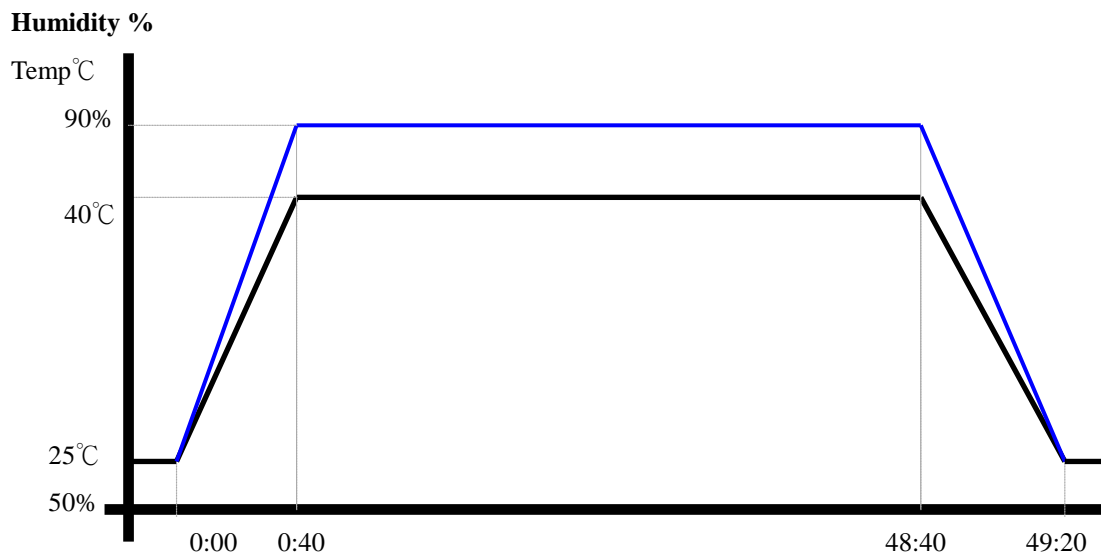
Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/09/14
Serial Number: 2582

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 90%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run 3DMark06
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-315D V2)

Test Result:

No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 04-20~21-2015

Test Product: AGD-315D V2

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

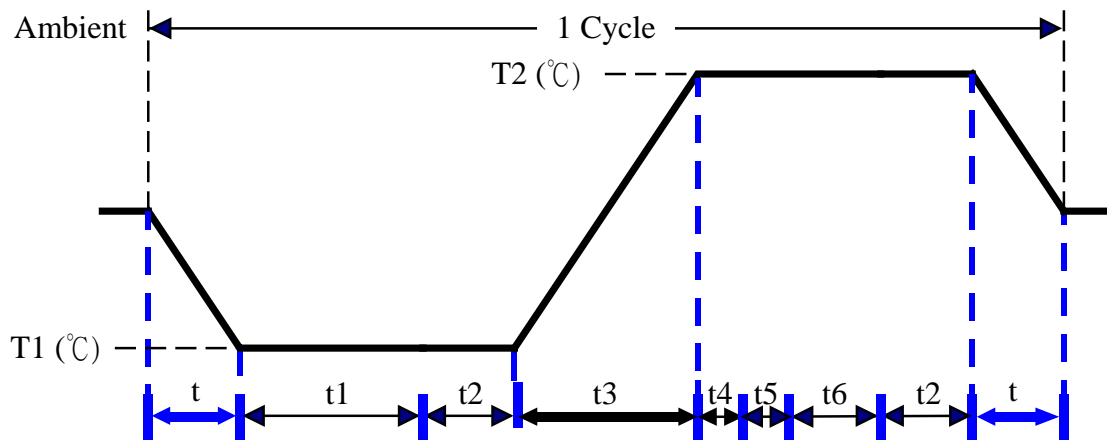
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D4H+-100

Date of Calibration: 10/09/14

Serial Number: 2582

Test Condition:



Parameters	Description
T1	-5°C
T2	55°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope

t , t1, t6: Power Off

t2: Power on/off test 10 times (on 2 min / off 5min)

t3, t4: 3DMARK' 06

t5: Windows XP Software restart test 3 times

Test Software: Windows XP

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.